

# Brian T Zutter

## List of Publications by Year in descending order

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#	ARTICLE	IF	CITATIONS
1	Thermometry of Silicon Nanoparticles. <i>Physical Review Applied</i> , 2018, 9, .	1.5	14
2	Orientation- Controlled Selective- Area Epitaxy of III- V Nanowires on (001) Silicon for Silicon Photonics. <i>Advanced Functional Materials</i> , 2020, 30, 2002220.	7.8	12
3	Electron-Transparent Thermoelectric Coolers Demonstrated with Nanoparticle and Condensation Thermometry. <i>ACS Nano</i> , 2020, 14, 11510-11517.	7.3	11
4	Visualizing the Electron Wind Force in the Elastic Regime. <i>Nano Letters</i> , 2021, 21, 10172-10177.	4.5	8
5	Differential electron yield imaging with STXM. <i>Ultramicroscopy</i> , 2021, 222, 113198.	0.8	2
6	In Situ Scanning Transmission Electron Microscopy (STEM) of Individual Electrochemical Intercalation Events in Graphite. <i>Microscopy and Microanalysis</i> , 2015, 21, 1193-1194.	0.2	1
7	Aluminum Nanoparticles as Fiducials for Nanoscale Temperature Measurements. <i>Microscopy and Microanalysis</i> , 2016, 22, 830-831.	0.2	1
8	Aloof Beam Plasmons in Silver Nanoparticles. <i>Microscopy and Microanalysis</i> , 2016, 22, 1642-1643.	0.2	1
9	Temperature Dependence of the Silicon Nitride Volume Plasmon. <i>Microscopy and Microanalysis</i> , 2016, 22, 1574-1575.	0.2	1
10	STEM EBIC Mapping of the Metal-Insulator Transition in Thin-film NbO <sub>2</sub> . <i>Microscopy and Microanalysis</i> , 2017, 23, 1428-1429.	0.2	1
11	Mapping Charge Recombination and the Effect of Point-Defect Insertion in GaAs Nanowire Heterojunctions. <i>Physical Review Applied</i> , 2021, 16, .	1.5	1
12	Temperature Dependence of the Volume Plasmon in Silicon Nanoparticles. <i>Microscopy and Microanalysis</i> , 2016, 22, 296-297.	0.2	0
13	Asymmetric Temperature Profiles in Joule-Heated in Aluminum Nanowires. <i>Microscopy and Microanalysis</i> , 2016, 22, 772-773.	0.2	0
14	Plasmon Energy Mapping in Aluminum and Indium with Sub-Nanometer Resolution. <i>Microscopy and Microanalysis</i> , 2017, 23, 378-379.	0.2	0
15	Detailed In Situ Observations of Electromigration in Aluminum Wires. <i>Microscopy and Microanalysis</i> , 2017, 23, 1450-1451.	0.2	0
16	In Situ Observation of Cooling in a Bismuth Telluride and Bismuth-Antimony Telluride Nanoscale Heterojunction. <i>Microscopy and Microanalysis</i> , 2017, 23, 1996-1997.	0.2	0
17	Electromigration of Copper in Lithographically-Defined Aluminum Nanowires. <i>Microscopy and Microanalysis</i> , 2018, 24, 2190-2191.	0.2	0
18	Mapping Electronic State Changes with STEM EBIC. <i>Microscopy and Microanalysis</i> , 2019, 25, 1396-1397.	0.2	0

#	ARTICLE	IF	CITATIONS
19	Inducing Electrically-Active Defects in a Gallium Arsenide Nanowire with an Electron Beam. <i>Microscopy and Microanalysis</i> , 2019, 25, 1618-1619.	0.2	0
20	Silicon Photonics: Orientation- and Area Epitaxy of III-V Nanowires on (001) Silicon for Silicon Photonics ( <i>Adv. Funct. Mater.</i> 30/2020). <i>Advanced Functional Materials</i> , 2020, 30, 2070203.	7.8	0
21	Correlation of Joule Heating and Electromigration-induced Mass Transport within Nanoscale Co Interconnects by In Situ STEM. <i>Microscopy and Microanalysis</i> , 2020, 26, 152-154.	0.2	0
22	Electrical Isolation Preserved by Plasma Focused Ion Beam TEM Sample Preparation and Verified with STEM SEEBIC Imaging. <i>Microscopy and Microanalysis</i> , 2020, 26, 194-195.	0.2	0